

Notice of References Cited	Application/Control No. 10/032,729	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner John L. Shew	Art Unit 2616	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0154634 A1	10-2002	Basso et al.	370/390
*	B	US-6,658,014 B1	12-2003	Tezuka, Yasuo	370/412
*	C	US-4,809,269	02-1989	Gulick, Dale E.	370/462
*	D	US-6,269,081 B1	07-2001	Chow et al.	370/241
*	E	US-2003/0043803 A1	03-2003	Hooper, Donald F.	370/390
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.